

Annex I



No. 0P171219.NQU00

1. SC 3 (SIL 3 Capability):
The product has met manufacturer design process requirements of Safety Integrity Level (SIL) 3. These are intended to achieve sufficient integrity against systematic errors of design by the manufacturer
2. A Safety instrumented Function (SIF) designed with this product must not be used at a SIL level higher than stated
3. Random Capability:
The SIL limit imposed by the Architectural Constraints for each element.
4. IEC 61508 Failure Rates in FIT*
For product used in a final element assembly, SIL must be verified for the specific application using the following failure rate data.

Failure rates for the product in FIT*

Failure Category	NTS-C/CPXX
λ_{sd}	>377.75
λ_{su}	0
λ_{dd}	2
λ_{du}	0
λ_{Total}	379.75
SFF	>90%
PFH	$3.8 \cdot 10^{-8}$ (h-1)

5. SIL Verification: The Safety Integrity Level (SIL) of an entire Safety Instrumented Function (SIF) must be verified via a calculation of PFD_{AVG} considering redundant architectures, proof test interval, proof test effectiveness, any automatic diagnostics, average repair time and the specific failure rates of all products included in the SIF. Each subsystem must be checked to assure compliance with minimum hardware fault tolerance (HFT) requirements.

* FIT = 1 failure / 10E9 hours